



US007313288B2

(12) **United States Patent**
Dierickx

(10) **Patent No.:** **US 7,313,288 B2**

(45) **Date of Patent:** **Dec. 25, 2007**

(54) **DEFECT PIXEL CORRECTION IN AN IMAGE SENSOR**

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 370 days.

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(21) Appl. No.: **11/111,287**

(22) Filed: **Apr. 20, 2005**

(65) **Prior Publication Data**

US 2006/0239580 A1 Oct. 26, 2006

(51) **Int. Cl.**

G06K 9/40 (2006.01)
G06K 9/00 (2006.01)
G06K 9/32 (2006.01)

(52) **U.S. Cl.** **382/274; 382/149**

(58) **Field of Classification Search** 382/149,
382/162, 164, 165, 167, 219, 272, 260-264,
382/274-277; 348/246; 358/515, 518

See application file for complete search history.

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(57) **ABSTRACT**

A method and apparatus for defect pixel correction in an image sensor. The method may include calculating a median of extrapolated values of right neighboring and left neighboring pixel values of a potentially defective pixel.

20 Claims, 6 Drawing Sheets

